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Re	М	2001/0012223	08/01	Kohyama						
	AB	2002/0030221	03/02	Sandhu et al.						
	AC	2002/0098654	07/02	Durcan et al.						
	AD	2002/0153614	10/02	Ema et al.						
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٨		OTHER REFER	ENCES (in	cluding Author, Title,	Date, Pertine	ent Pages,	, Etc	.)	٠	
25	AM	Kim, D.H. et al., "A	Mechanical	ly Enhanced Storage Noc	de for Virtually	Unlimited	Heig	ght (M	ESH)	
MC		Capacitor Aiming	g at Sub 70n	m DRAMs", IEEE Jan. 2	2004, pp. 69-72	,				
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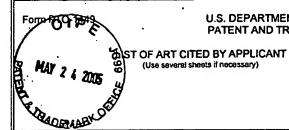
LIST OF ART CITED BY APPLICANT
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APPLICANT: H. Montgomery Manning et al.

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OTHER RE	FEREN	ICES (including Author,	, Title, Date, Pe	ertinent Pages, Etc.)					
MY	AF .	J. P. O'Sullivar	n et al., The mo	norphology and mechanism	π of formatio	n of poro	us anodic f	films on aluminit	um,
	$\perp \downarrow$	PROC. Ro	JY. SOC. LOND.	. A, Vol. 317, pp. 511-543	(1970)				
	AG	S. Shingubara	, Fabrication o	of nanomaterials using por	rous alumina	ı template	es, J. Nanoi	PARTICLE RES., '	Vol. 5,
		pp. 17-30) (2003).						
	АН	S. Tan et al., F	ligh Aspect Re	atio Microstructures on Po	rous Anodic	: Aluminu	m Oxide, IE	EE, pp. 267-27	2 (1995).
	A)	J. Liang et al.,	Nonlithograph	hic Fabrication of Lateral S	Superlattices	; for Nano	metric Elec	ctromagnetic-Op	otic
		IEEE J. S	ELECTED TOPK	CS IN QUANTUM ELECTR., V	√ol. 8, No. 5,	, pp. 998-	1008 (Sept	/Oct 2002).	
	~	V. V. Konovalc	ov et al., Chem	nistry of Materials, CHEM. N	MATER., Vol.	11, No. 8	3, pp. 1949-	-1951 (August 1	999).
<u> </u>	AK	H. Masuda et a	al., Highly orde	ered nanochannel-array ar	rchitecture ir	n anodic ı	alumina, Aç	op. Phys. Lett, V	/ol. 71,
Ato		No. 19, pp. 27	70-2772 (Nove	ember 1997).					
EXAMINER	6	DATE CONSIDE	:RED	10,5	1/2/	1	12,	121/0	·
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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APPLICANT: H. Montgomery Manning et al.

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OTHER RE	FERENC	CES (including Author,	Title, Date, Pe	rtinent Pages, Etc.)				
AC	M	D. Crouse et al.	., Self-Assemb	oled Nanostructures Using Anodized Alum	nina Thin f	ilms for Op	toelectroni	c
		Application	ns, IEEE, pp. 2	234-235 (1999).		· · · · · · · · · · · · · · · · · · ·		
	M	A. Nadeem et a	I., Fabrication	of Microstructures Using Aluminum Anod	lization Te	chniques, p	p. 274-277	
		(pre-2004)).					
7	AO	C. Y. Liu et al.,	Ordered anod	ic alumina nanochannels on focused-ion-	beam-pre	patterned a	luminum su	ırface
Ma		Appl. Phys	s. Lett., Vol. 78	I, No. 1, pp. 120-122 (January 2001).				
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Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date # Appropriate
AC	М	6,204,143	3/2001	Roberts et al.			
	AB	6,180,450	1/2001	Dennison			
	AC	5,340,763	8/1994	Dennison			
	A 0	6,403,442	6/2002	Reinberg			
	Æ	6,037,218	3/2000	Dennison et al.			
	AP	5,652,164	7/1997	Dennison et al.			
	40	5,498,562	12/1996	Dennison et al.			
7	AH	5,401,681	3/1995	Dennison et al.			
Ae	N	5,605,857	2/1997	Jost et al.			

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OTHER REFERE	NCES (including Author, Title, Date, Pertinent Pages, Etc.)
100-	PCT/US2004/027898; Filed: 8/26/2004; PCT Search Report malled 2/28/2005; 4 pp.
~ 34	"Novel Robust Cell Capacitor (Leaning Exterminated Ring Type Insulator) And New Storage Node Contact (Top Spacer Contact) For 70nm DRAM Technology And Beyond"; Park et al.;
Mc L	2004 Symposium on VLSI Technology Digest of Technical Papers; 7/2004; pp. 34-35.
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LIST OF ART CITED BY APPLICANT

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OTHER RE	FEREN	ICES (including Author,	Title, Date, Per	rtinent Pages, Etc.)					
Me	. АМ	Banhart, Alumi	inum Foams: O	n the Road to Real Appli	ications, MRS Bui	LLETIN, PP	. 290-295 (April 2003).
	AN	Gibson et al., C	Cellular Solids,	MRS BULLETIN, pp. 270-2	274 (April 2003).				
							- <u>-</u>		
	AO			s: Intriguing Structures, I	Novel Properties,	and Innov	vative Appli	cations, M	RS ———
EXAMINER		BULLETIN,	pp. 296-300 (A	April 2003).					
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*EXAMINER: considered.	Initial i	reference considered, whe	ther or not citation to	n is in conformance with MP applicant.	EP 609; Draw line to	hrough cita	tion if not in c	conformance	and not

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT: H. Montgomery Manning et al.

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OTHER RE	FEREN	CES (including Author,	Title, Date, Pe	ertinent Pages, Etc.)			
AC	AM	Green et al., 77	ne Structure ai	nd Applications of Cellular Ceramics, WEB	Extra, 1	0 pages (Ap	oril 2003).
			······································	March Control			
	AN	Karp et al., Sca	ffolds for Tiss	ue Engineering, MRS Bulletin, pp. 301-306	(April 20	003).	
				•			
-1	AO	Kraynik, Foam	Structure: Fro	m Soap Froth to Solid Foams, MRS BULLE	TIN, pp. 2	75-276 (Apı	il 2003).
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2295

SERIAL NO. 10/733,181

LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT: H. Montgomery Manning et al.

FILING DATE December 10, 2003

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OTHER RE	FEREN	CES (including Author,	Title, Date, Pe	ertinent Pages, Etc.)			
AC.	АМ	Maire et al., In	Situ X-Ray To	mography Measurements of Deformation i	n Cellula	r Solids, MR	RS BULLETIN,
	Ì	pp. 284-2	89 (April 2003).			
	AN	Oh et al., Prep	aration and Po	re-Characteristics Control of Nano-Porous	Material	s Using Org	anometallic
		Building E	Blocks, 4 Carb	ON SCIENCE, No. 1, pp. 1-9 (March 2003).			
	AO	Onck, Scale E	ffects in Cellula	ar Metals, MRS Bulletin, pp. 279-283 (Api	ril 2003).		
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SERIAL NO. 10/733,181

LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT: H. Montgomery Manning et al.

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M	АМ	Park et al., Bl	ock Copolymer	Lithography: Periodic Arr	rays of ~10 ¹¹ Hole	s in 1 Sq	uare Centir	meter,
1		276 Scie	nce, pp. 1401-1	1404 (May 30, 1997).			,	
	AN	Tsukada et al	., Preparation a	nd Application of Porous	Silk Fibroin Mater	rials, 54 J	OURNAL OF	APPLIED POLYME
AC		SCIENCE	, pp. 507-514 (1	994).		·		
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